Search Notes

Application/Control No.	Applicant(s)/Patent Under Reexamination
10562458	BREDERLOW ET AL.
Examiner	Art Unit
JOHN F MORTELL	4154

SEARCHED					
Class	Subclass	Date	Examiner		
340	572.100	3/10/2008	/JM/		

SEARCH NOTES				
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PALM Inventor Name Search	3/10/2008	/JM/		
EAST Search Notes Included	3/5-3/13/2008	/JM/		
NPL: ACM Digital LIbrary: AC RFID tag	3/19/2008	/JM/		
Confer with Benjamin Lee, Supervisory Patent Examiner	5/4/2009	/JM/		
EAST: update search; search notes included.	5/11/2009	/JM/		
Confer with Daniel Wu, Supervisory Patent Examiner	11/19/2009	/JM/		
EAST: update search; search notes included.	11/19, 12/2/2009	/JM/		

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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